

X-Ray Photoelectron Spectroscopy (XPS)

Category:

C. Particle Characterisation in and ex-situ

Institute: Uppsala University (UU)

Location: Ångström Laboratory
Lägerhyddsv. 1, Uppsala, Sweden

Contact Details of Technology Expert:

Fredric Ericson

Phone: +46 (0)18 471 3090

Fax: +46 (0)18 471 3380

E-mail: fredric.ericson@angstrom.uu.se

Short Technology Description

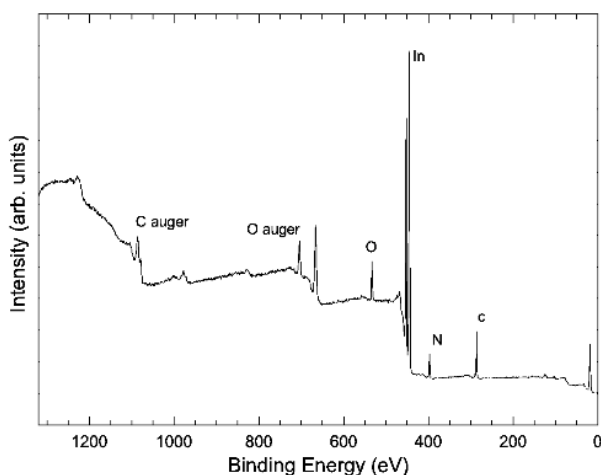
XPS or ESCA (electron spectroscopy for chemical analysis) is a surface analysis method used to determine elemental composition on a sample surface. Additional information about chemical bonds can be obtained from chemical shifts in the spectra. Ar ion milling is employed for depth profiling.

Main Features (Equipment Capabilities):

Physical Electronics Quantum 2000

- X-ray beam excitation, lateral resolution 10 µm
- Analysis depth resolution 1-5 nm
- Ar ion gun
- Ultra High Vacuum

Typical Samples & Images:



Any further Information: